CLAIMS

1. A apparatus for interfacing a socket to a testing apparatus which comprises:

a base member;

a first electrically conductive contact member being removably attachable to the base member;

the first contact member having a first portion thereof sized and shaped to engage an electrical contact on the testing apparatus and a second portion thereof sized and shaped to engage a second contact member;

a second contact member having a first portion thereof sized and shaped to engage the second portion of the first contact member; and

the second contact member being removably and electrically connectable to the socket.

2. The apparatus of claim 1 further comprising:

a plurality of first and a plurality of second contacts, each arranged in pairs of sets; and

each of the second contacts being removably attachable to a separate electrical connection with the socket.

3. The apparatus of claim 2 wherein the first contacts are removably attachable to the base member by at least one clamp mechanism and connections between first and second contacts are facilitated by the clamp mechanism.

4. The apparatus of claim 1 wherein the first contact is removably attachable to the base member by a clamp mechanism and the connection between the first and the second contacts is facilitated by the clamp mechanism.

5. The apparatus of claim 4 further comprising a socket base having at least one pin receptacle electrically connected to the second contact where the pin receptacle is sized and shaped to removably engage a pin in the socket.

6. The apparatus of claim 3 further comprising a socket base having a plurality of pin receptacles each electrically connected to a separate one of the plurality of second contacts, where each pin receptacle is sized and shaped to removably engage a pin in the socket.

7. The apparatus of claim 2 further comprising a socket base having a plurality of pin receptacles each electrically connected to a separate one of the plurality of second contacts, where each pin receptacle is sized and shaped to removably engage a pin in the socket.

8. The apparatus of claim 1 further comprising a socket base having at least one pin receptacle electrically connected to the second contact where the pin receptacle is sized and shaped to removably engage a pin in the socket.

9. A system for testing an electronic device which comprises:

a testing apparatus including a test fixture for interfacing with electronic devices to be tested;

a base member;

a first electrically conductive contact member being removably attachable to the base member;

the first contact member having a first portion thereof sized and shaped to engage an electrical contact on the test fixture and a second portion thereof sized and shaped to engage a second contact member;

a second contact member having a first portion thereof sized and shaped to engage the second portion of the first contact member; and

the second contact member being removably and electrically connectable to the socket.

10. The system of claim 9 further comprising:

a plurality of first and a plurality of second contacts, each arranged in pairs of sets; and

each of the second contacts being removably attachable to a separate electrical connection with the socket.

11. The system of claim 10 wherein the first contacts are removably attachable to the base member by at least one clamp mechanism and connections between first and second contacts are facilitated by the clamp mechanism.

12. The system of claim 9 wherein the first contact is removably attachable to the base member by a clamp mechanism and the connection between the first and the second contacts is facilitated by the clamp mechanism.

13. The system of claim 12 further comprising a socket base having at least one pin receptacle electrically connected to the second contact where the pin receptacle is sized and shaped to removably engage a pin in the socket.

14. The system of claim 11 further comprising a socket base having a plurality of pin receptacles each electrically connected to a separate one of the plurality of second contacts, where each pin receptacle is sized and shaped to removably engage a pin in the socket.

15. The system of claim 10 further comprising a socket base having a plurality of pin receptacles each electrically connected to a separate one of the plurality

of second contacts, where each pin receptacle is sized and shaped to removably engage a pin in the socket.

16. The system of claim 9 further comprising a socket base having at least one pin receptacle electrically connected to the second contact where the pin receptacle is sized and shaped to removably engage a pin in the socket.

17. A method for interfacing a relatively small number of electrical devices to be tested with a high volume testing device comprising the acts of:

attaching a first set of contacts to the testing device;

removably fixing a second set of contacts in contact with the first set of contacts;

attaching a removable electrical socket to the second set of contacts; and

placing a device to be tested within the socket.